

# **Design and behavioral simulation of comparator based switched-capacitor circuits**

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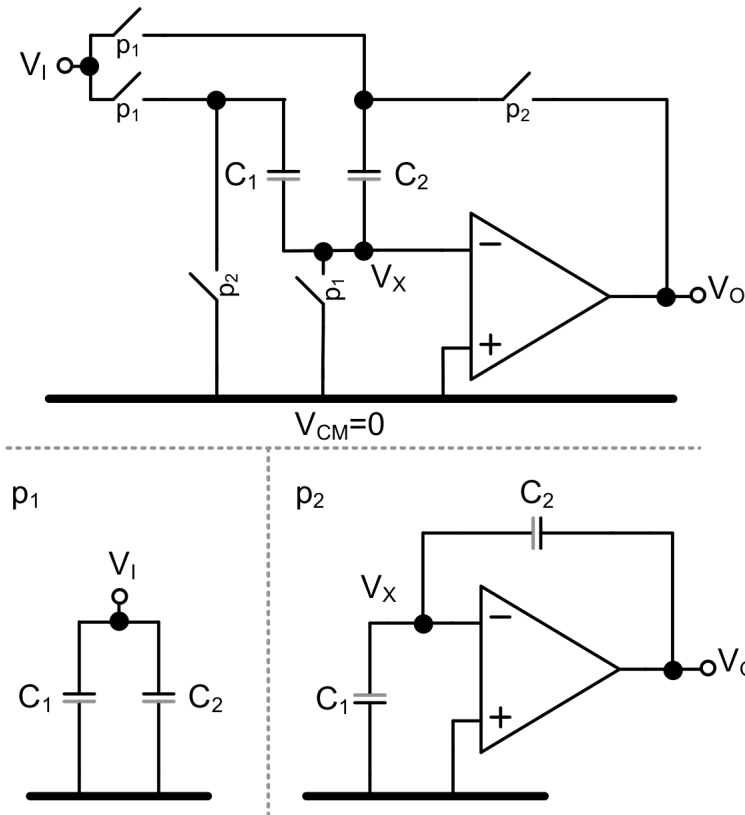
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# Outline

- **Motivation**
- **Comparator based switched capacitor circuits**
- **Design equations**
- **Example of a comparator-based switched-capacitor circuit**
- **Future work**

# Motivation: Why CBSC

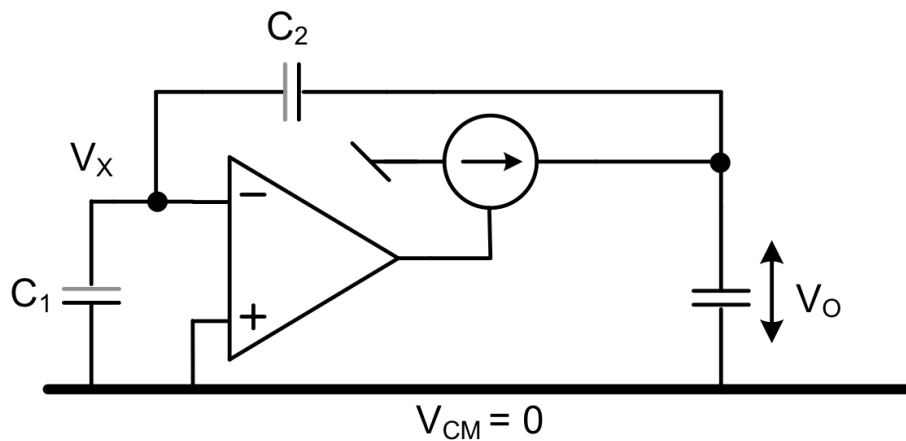
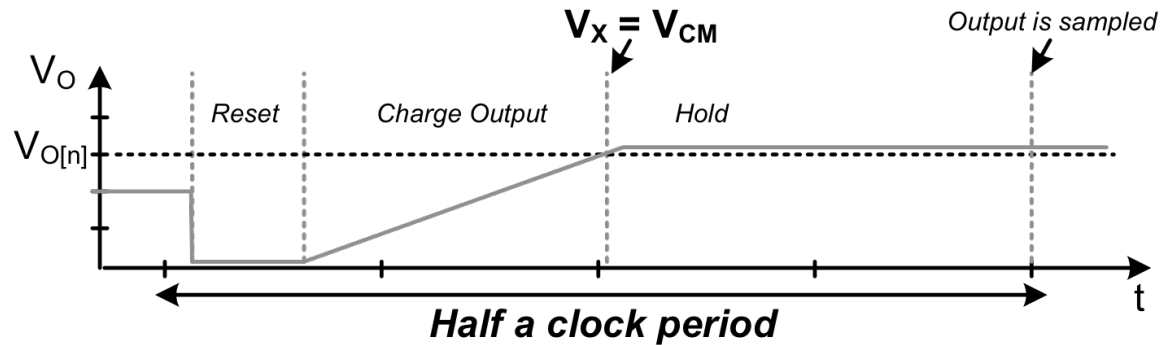
## Conventional switched-capacitor amplifier



- An amplifier used in pipelined ADCs
- In nano-scale technologies (< 100nm) the supply voltage and transistor output resistance is low.
- Harder to design efficient high-gain (>40dB) OTAs
- Is there an alternative to OTA based switched-capacitor?

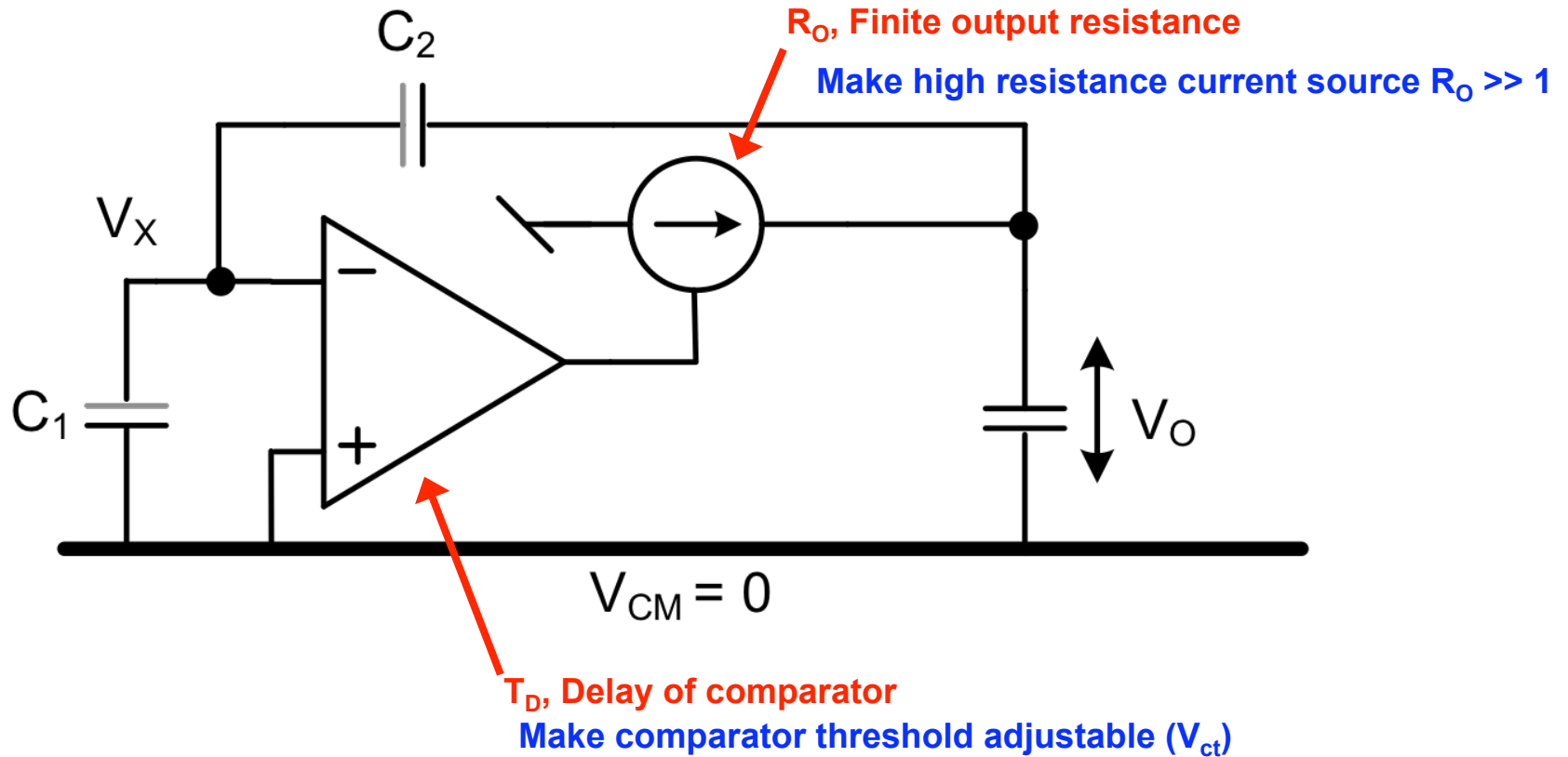
$$H_0(z) = 1 + \frac{C_1}{C_2} z^{-1} \xrightarrow{\text{Finite OTA gain}} H_1(z) = H_0(z) \times \frac{1}{1 + \frac{H_0(1)}{A}}$$

# Comparator-based switched capacitor circuits



- Introduced in [1]
- OTA replaced by current source and comparator
- Detects virtual ground
- Easier to make high impedance current sources and a fast comparator than a OTA
- An OTA needs to be stable in a feedback loop, a comparator does not

# Non-ideal effects



# The design equations

- With these two effects the output voltage of the CBSC amplifier is

$$V_o = 2e^{\frac{-T_d}{R_o C_o}} + I_o R_o \left[ 1 - e^{\frac{-T_d}{R_o C_o}} \left( 1 + 2 \frac{V_{ct}}{I_o R_o} \right) \right]$$

Gain of amplifier

Overshoot caused by comparator delay

1. Required sampling capacitor (from [2])      3. Required output resistance

$$C = a_1 \frac{48kT2^{2B}}{V_{pp}^2}$$

$$R_o = \frac{-T_d}{\ln(1 - \epsilon_g) C_o}$$

2. Necessary current

$$I_o = C_o \frac{(V_{pp}/4 + V_{cm})}{1/2 f_s - T_r}$$

4. Required comparator threshold

$$V_{ct} = -\frac{1}{2} I_o R_o \left( 1 - e^{\frac{T_d}{R_o C_o}} \right)$$

Given:

$T_d$  = Comparator delay

$\epsilon_g$  = Gain error

$V_{pp}$  = Peak to peak output voltage

$T$  = Temperature

$B$  = Number of bits

$k$  = Boltzmann's constant

$a_1$  = constant

$T_r$  = reset time

$V_{cm}$  = Common mode voltage

$f_s$  = sampling frequency

Calculate:

$I_o$  = Current in current source

$R_o$  = Output resistance

$C$  = Sampling capacitor

$V_{ct}$  = Comparator threshold

# The example system

## Given

Parameter	Value
B	9
T	300K
k	1.38e-23
$a_1$	3
$V_{PP}$	1V
$V_{CM}$	0.6V
$\epsilon_g$	$1/(2^B)$
$T_d$	0.5ns
$T_r$	1ns
fs	50MHz

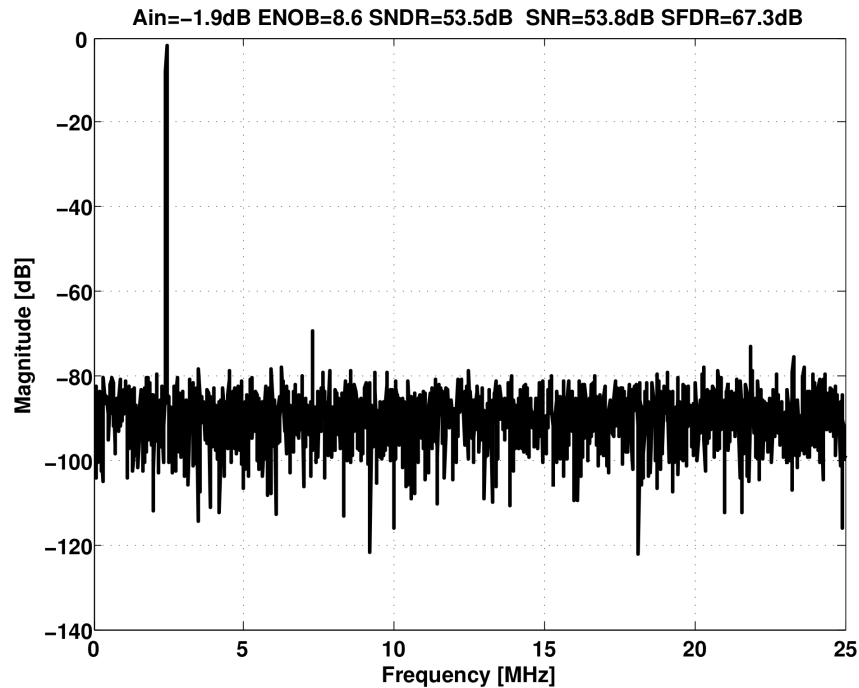
## Calculated

Parameter	Value
C	160fF
$I_o$	30 $\mu$ A
$R_o$	1.1M $\Omega$
$V_{ct}$	32mV

# Simulation results

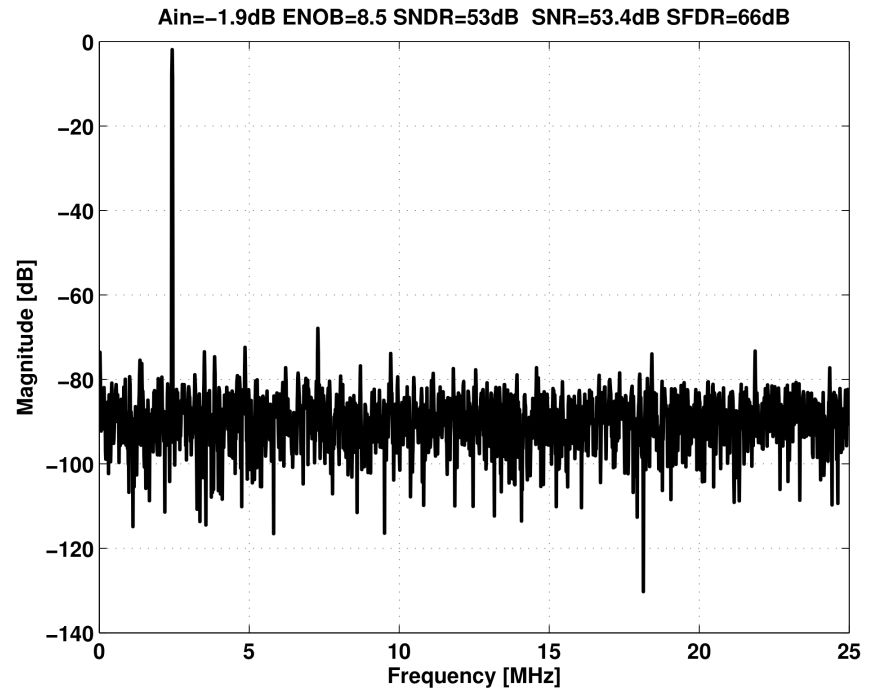
## MATLAB MODEL

Design equations



## SPICE MODEL

Macro model of real circuit



< 7 % Difference for SNDR and SNR

Both models can be downloaded from <http://www.wulff.no/carsten> . Tools & Scripts,  
Behavioral model of comparator-based switched-capacitor circuits



## Conclusion

- Design equations give can quickly produce values for macro model simulation
- Design equations predicts the required parameters with high accuracy (less than 7% error for SNDR and SNR)

## References

1. **T. Sepke, J. K. Fiorenza, C. G. Sodini, P. Holloway, and H.-S. Lee, “Comparator-based switched-capacitor circuits for scaled CMOS technologies,” in ISSCC Digest of Technical Papers, 2006, pp. 220–221.**
2. **C. Wulff and T. Ytterdal, “Design Of A 7-bit, 200MS/s, 2mW Pipelined ADC With Switched Open-Loop Amplifiers In A 65nm CMOS Technology,” in Proc. NORCHIP 2007**